

Microbeam analysis — Electron probe microanalysis — Guidelines for qualitative point analysis by wavelength dispersive X-ray spectrometry

ICS 71.040.99

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National foreword

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The UK participation in its preparation was entrusted to Technical Committee CII/9, Microbeam analysis, which has the responsibility to:

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- present to the responsible international/European committee any enquiries on the interpretation, or proposals for change, and keep the UK interests informed;
- monitor related international and European developments and promulgate them in the UK.

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Summary of pages

This document comprises a front cover, an inside front cover, the ISO title page, pages ii to v, a blank page, pages 1 to 10, an inside back cover and a back cover.

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microanalysis — Guidelines for
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dispersive X-ray spectrometry**

*Analyse par microfaisceaux — Analyse par microsonde électronique
(Microsonde de Castaing) — Lignes directrices pour l'analyse
qualitative ponctuelle par spectroscopie de rayons X à dispersion de
longueur d'onde*



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Foreword

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ISO 17470 was prepared by Technical Committee ISO/TC 202, *Microbeam analysis*, Subcommittee SC 2, *Electron probe microanalysis*.